



EMI TEST REPORT

Test Report No. : 32KE0169-HO-B

Applicant : SHARP CORPORATION
Type of Equipment : Cellular Phone
Model No. : SH-10D
FCC ID : APYHRO00173
Test standard : FCC Part 15 Subpart B: 2012 Class B
Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test:

July 9, 2012

Representative test engineer:

Hiroshi Kukita

Engineer of WiSE Japan,
UL Verification Service

Approved by:

Masanori Nishiyama
Leader of WiSE Japan,
UL Verification Service



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation. *As for the range of Accreditation in NVLAP, you may refer to the WEB address, <http://www.ul.com/japan/jpn/pages/services/emc/about/mark1/index.jsp#nvlap>

UL Japan, Inc.

Head Office EMC Lab.

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13-EM-F0429

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SECTION 1: Customer information

Company Name : SHARP CORPORATION
Address : 2-13-1 Iida, Hachihonmatsu, Higashi-Hiroshima City, Hiroshima,
739-0192 Japan
Telephone Number : +81-82-420-1826
Facsimile Number : +81-82-420-1829
Contact Person : Kazuo Sugimoto

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Cellular Phone
Model No. : SH-10D
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : July 6, 2012
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product description

Feature of EUT : LTE(FDD1) and Tetra-band WCDMA(FDD I / V / VI / XIX) and
Tetra-band GSM(850/900/1800/1900)
Cellular Phone / Bluetooth/W-LAN , Felica & 1.5GHz Band Satellite
Receiver (GPS) enable
- GSM (EU:900/1800M, 1900M, US:850M)
- WCDMA (EU:2000M, US:850M, JPN: 800/2000)
Clock frequency(ies) in the system : CPU: 1.512GHz
Source oscillation:19.2MHz

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SECTION 3: Test specification, procedures & results

3.1 Test specification

Test Specification : FCC Part 15 Subpart B: 2012, final revised on May 17, 2012 and effective June 18, 2012

Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	FCC: ANSI C63.4: 2003 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 12.3dB 3.80200MHz, L [AV] 14.8dB 2.04740MHz, L	Complied
Radiated emission	FCC: ANSI C63.4: 2003 8. Radiated emission measurements	Class B	N/A	6.0dB 798.199MHz, Vertical, QP	Complied

*Note: UL Japan, Inc's EMI Work Procedure 13-EM-W0420.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (+dB)
	150kHz-30MHz
No.1	3.5dB
No.2	3.6dB
No.3	3.6dB
No.4	3.6dB

Test room (semi-anechoic chamber)	Radiated emission (10m*)(±dB)		
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz
No.1	4.2dB	5.0dB	4.8dB
No.2	-	-	-
No.3	-	-	-
No.4	-	-	-

*10m = Measurement distance

Test room (semi-anechoic chamber)	Radiated emission						
	(3m*)(+dB)				(1m*)(+dB)		(0.5m*)(+dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -10GHz	10GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	4.3dB	5.0dB	5.1dB	4.9dB	5.8dB	4.4dB	4.3dB
No.2	4.3dB	5.2dB	5.1dB	5.0dB	5.7dB	4.3dB	4.2dB
No.3	4.6dB	5.0dB	5.1dB	5.0dB	5.7dB	4.5dB	4.2dB
No.4	4.8dB	5.2dB	5.0dB	5.0dB	5.7dB	5.2dB	4.2dB

*3m/1m/0.5m = Measurement distance

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. *NVLAP Lab. code: 200572-0
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN
Telephone : +81 596 24 8116 Facsimile : +81 596 24 8124

	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

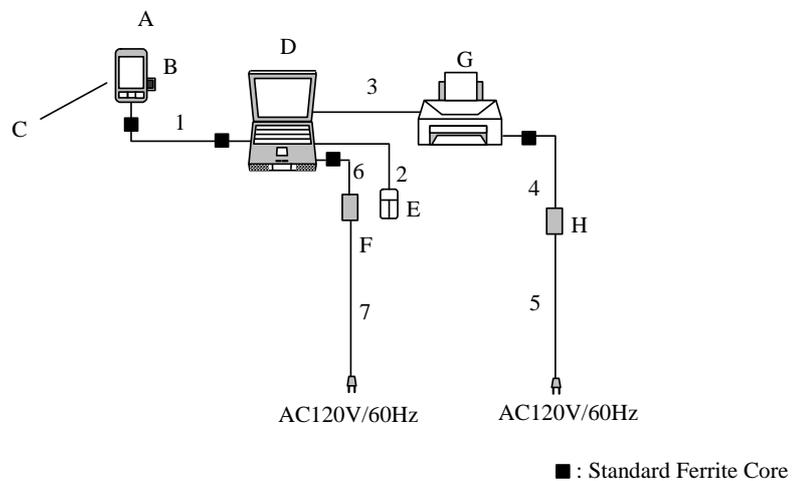
Refer to APPENDIX.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating modes

The mode(s) : 1) USB Data Com Mode
The USB data is communicated between EUT and Personal computer (Pair of EUT).
2) Standby Mode
Standby state for USB communication.

4.2 Configuration and peripherals



* Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remarks
A	Cellular Phone	SH-10D	004401114085414	SHARP CORPORATION	EUT
B	microSD Memory Card	SD-C08G	0852K93900Y	TOSHIBA	-
C	Lithium-Ion Battery	Battery Pack SH38	-	SHARP CORPORATION	EUT
D	Personal Computer	PP11L	CN-0D4571-48643-58P-1053	DELL	-
E	Mouse	M-UAG120	G83C0007F310	TOSHIBA	-
F	AC Adapter (PC)	PA-1650-05D2	CN-0F7970-71615-77H-0D63	DELL	-
G	Printer	C6410A	8G8BA1W18J	Hewlett Packard	-
H	AC Adapter(Printer)	AT-3018A-0101	C4557-60004	Hewlett Packard	-

List of cables used

No.	Name	Length (m)	Shield		Remarks
			Cable	Connector	
1	USB Data Cable	1.15	Shielded	Shielded	-
2	Mouse Cable	0.71	Shielded	Shielded	-
3	Printer Cable	2.00	Shielded	Shielded	-
4	DC Power Cable(Printer)	2.00	Unshielded	Unshielded	-
5	AC Power Cable(Printer)	1.80	Unshielded	Unshielded	-
6	DC Power Cable(PC)	1.80	Unshielded	Unshielded	-
7	AC Power Cable(PC)	0.90	Unshielded	Unshielded	-

SECTION 5: Conducted Emission

5.1 Operating environment

Test place : No. 1 semi anechoic chamber.
Temperature : See data
Humidity : See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment. Photographs of the set up are shown in Appendix 3.

Frequency range : 0.15 MHz-30MHz
EUT position : Table top
EUT operation mode : See Clause 4.1

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type : Quasi-Peak and Average
IF Bandwidth : 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: July 9, 2012

Test engineer: Hiroshi Kukita

UL Japan, Inc.

Head Office EMC Lab.

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SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No. 1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The EUT was set on the edge of the tabletop.
Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength. Photographs of the set up are shown in Appendix 3.

6.3 Test conditions

Frequency range : 30MHz-300MHz (Biconical antenna) / 300MHz-1000MHz (Logperiodic antenna)
1000MHz-10000MHz (Horn antenna)
Test distance : 3m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity.
The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer.
The radiated emission measurements were made with the following detector function of the test receiver and the Spectrum analyzer.

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Spectrum Analyzer
IF Bandwidth	QP: BW 120kHz	PK: RBW:1MHz/VBW: 3MHz AV *1): RBW:1MHz/VBW:10Hz

*1) When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT and/or GPS antenna to see the position of maximum noise, and the test was made at the position that has the maximum noise.

6.5 Test result

Summary of the test results: Pass

Date: July 9, 2012

Test engineer: Hiroshi Kukita

UL Japan, Inc.

Head Office EMC Lab.

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APPENDIX 1: Data of EMI test

Conducted Emission

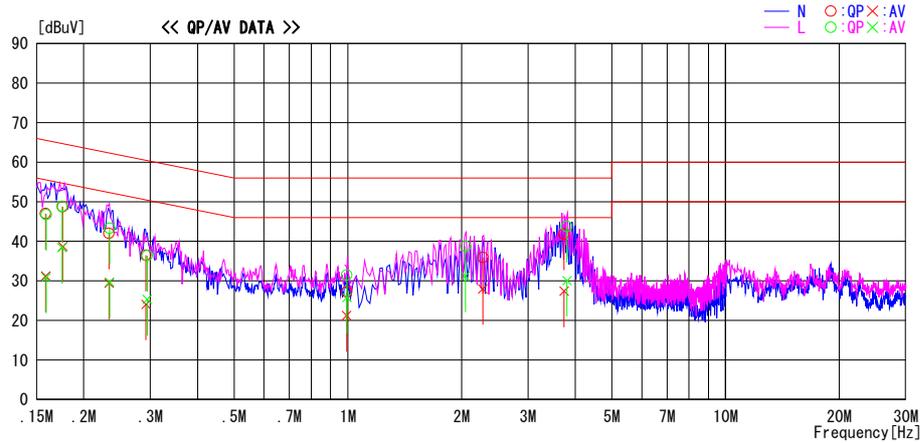
DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2012/07/09

Report No. : 32KE0169-H0
Temp./Humi. : 22deg. C / 55% RH
Engineer : Hiroshi Kukita

Mode / Remarks : USB Data Com Mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading		Corr. Factor	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15850	33.8	18.0	13.2	47.0	31.2	65.5	55.5	18.5	24.3	N	
0.17586	35.5	25.5	13.2	48.7	38.7	64.7	54.7	16.0	16.0	N	
0.23322	28.7	16.1	13.3	42.0	29.4	62.3	52.3	20.3	22.9	N	
0.29224	23.2	10.8	13.3	36.5	24.1	60.5	50.5	24.0	26.4	N	
0.99340	13.8	7.8	13.4	27.2	21.2	56.0	46.0	28.8	24.8	N	
2.27780	22.3	14.4	13.6	35.9	28.0	56.0	46.0	20.1	18.0	N	
3.73780	28.0	13.6	13.8	41.8	27.4	56.0	46.0	14.2	18.6	N	
0.15904	33.5	17.7	13.2	46.7	30.9	65.5	55.5	18.8	24.6	L	
0.17534	35.6	25.2	13.2	48.8	38.4	64.7	54.7	15.9	16.3	L	
0.23400	30.0	16.4	13.3	43.3	29.7	62.3	52.3	19.0	22.6	L	
0.29450	23.1	12.0	13.3	36.4	25.3	60.4	50.4	24.0	25.1	L	
0.99470	18.1	12.4	13.4	31.5	25.8	56.0	46.0	24.5	20.2	L	
2.04740	25.2	17.7	13.5	38.7	31.2	56.0	46.0	17.3	14.8	L	
3.80200	29.9	16.3	13.8	43.7	30.1	56.0	46.0	12.3	15.9	L	

CHART:WITH FACTOR,Peak hold data. CALCULATION:RESULT=READING+C.F(PROBE LOSS + CABLE LOSS)
Except for the above table : adequate margin data below the limits.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Conducted Emission

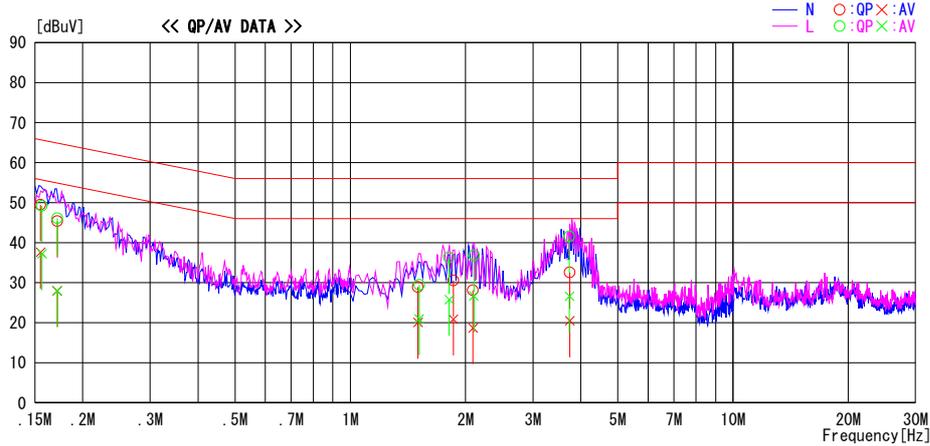
DATA OF CONDUCTED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2012/07/09

Report No. : 32KE0169-HO
Temp./Humi. : 22deg. C / 55% RH
Engineer : Hiroshi Kukita

Mode / Remarks : Standby Mode

LIMIT : FCC15.107(a) QP ClassB
FCC15.107(a) AV ClassB



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15502	36.3	24.4	13.2	49.5	37.6	65.7	55.7	16.2	18.1	N	
0.15641	36.0	24.0	13.2	49.2	37.2	65.7	55.7	16.5	18.5	L	
0.17146	32.2	14.8	13.2	45.4	28.0	64.9	54.9	19.5	26.9	N	
0.17164	32.9	14.8	13.2	46.1	28.0	64.9	54.9	18.8	26.9	L	
1.50280	15.4	6.6	13.5	28.9	20.1	56.0	46.0	27.1	25.9	N	
1.51390	16.0	7.5	13.5	29.5	21.0	56.0	46.0	26.5	25.0	L	
1.81141	22.8	12.3	13.5	36.3	25.8	56.0	46.0	19.7	20.2	L	
1.85780	17.1	7.4	13.5	30.6	20.9	56.0	46.0	25.4	25.1	N	
2.09290	14.6	5.2	13.5	28.1	18.7	56.0	46.0	27.9	27.3	N	
2.10290	23.3	13.2	13.5	36.8	26.7	56.0	46.0	19.2	19.3	L	
3.73860	27.8	12.8	13.8	41.6	26.6	56.0	46.0	14.4	19.4	L	
3.74663	18.8	6.7	13.8	32.6	20.5	56.0	46.0	23.4	25.5	N	

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT=READING+C.F (PROBE LOSS + CABLE LOSS)
Except for the above table : adequate margin data below the limits.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Below 1GHz)

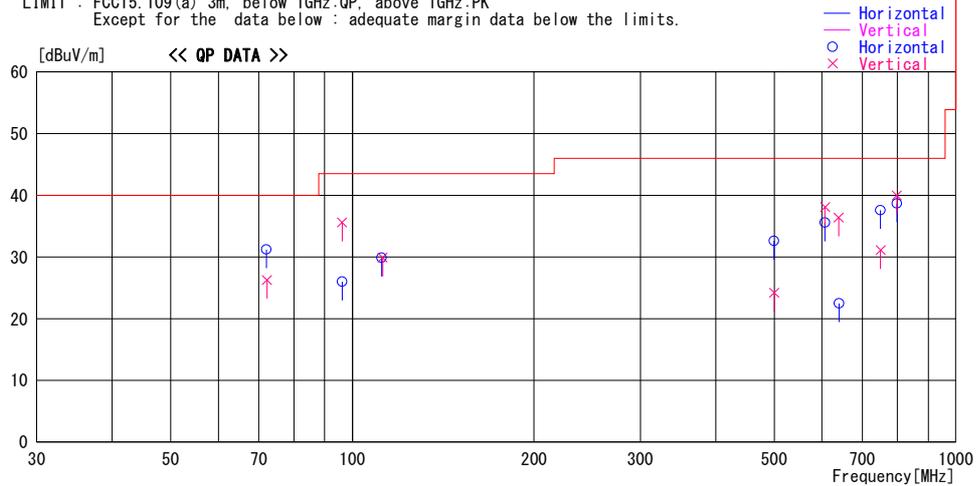
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No. 1 Semi Anechoic Chamber
Date : 2012/07/09

Report No. : 32KE0169-HO
Temp./Humi. : 22deg. C / 55% RH
Engineer : Hiroshi Kukita

Mode / Remarks : USB Data Com Mode, Worst axis: X axis

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level	Angle	Height	Polar.	Limit	Margin	Comment
			Factor	Gain							
			[dB/m]	[dB]	[dBuV/m]	[Deg]	[cm]		[dBuV/m]	[dB]	
72.023	55.4	QP	6.7	-30.9	31.2	109	241	Hori.	40.0	8.8	
72.204	50.6	QP	6.6	-30.9	26.3	223	100	Vert.	40.0	13.7	
96.134	57.0	QP	9.2	-30.6	35.6	141	100	Vert.	43.5	7.9	
96.135	47.4	QP	9.2	-30.6	26.0	64	250	Hori.	43.5	17.5	
111.760	48.6	QP	11.7	-30.4	29.9	111	153	Hori.	43.5	13.6	
112.241	48.5	QP	11.8	-30.4	29.9	219	100	Vert.	43.5	13.6	
499.814	40.8	QP	18.2	-26.4	32.6	7	211	Hori.	46.0	13.4	
500.000	32.3	QP	18.2	-26.3	24.2	114	100	Vert.	46.0	21.8	
607.133	41.6	QP	19.5	-25.5	35.6	158	121	Hori.	46.0	10.4	
607.134	44.1	QP	19.5	-25.5	38.1	355	100	Vert.	46.0	7.9	
639.088	41.8	QP	19.9	-25.3	36.4	0	100	Vert.	46.0	9.6	
639.960	27.9	QP	19.9	-25.3	22.5	124	100	Hori.	46.0	23.5	
749.990	34.5	QP	21.3	-24.7	31.1	353	100	Vert.	46.0	14.9	
749.991	41.0	QP	21.3	-24.7	37.6	105	100	Hori.	46.0	8.4	
798.199	42.4	QP	22.0	-24.4	40.0	68	122	Vert.	46.0	6.0	
798.360	41.1	QP	22.0	-24.4	38.7	146	100	Hori.	46.0	7.3	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Below 1GHz)

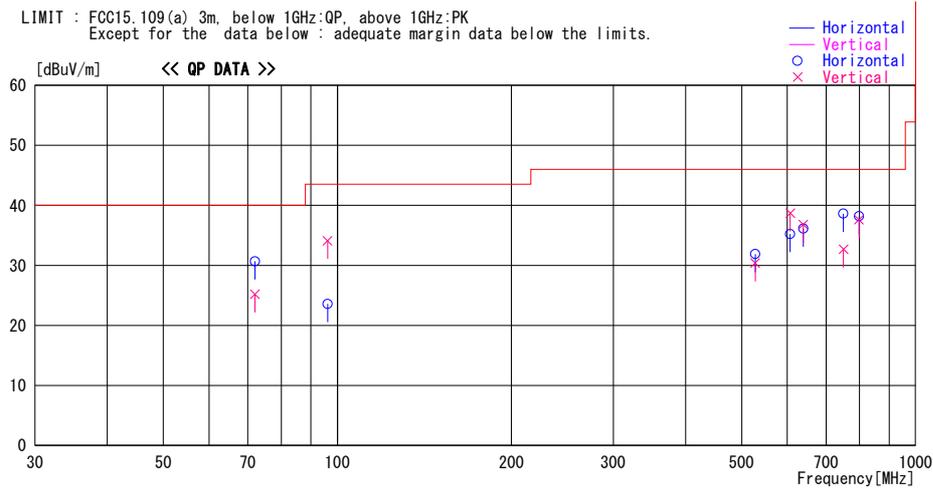
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2012/07/09

Report No. : 32KE0169-HO
Temp./Humi. : 22deg. C / 55% RH
Engineer : Hiroshi Kukita

Mode / Remarks : Standby Mode, Worst axis: X axis

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna		Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Loss& Gain [dB]							
72.023	54.9	QP	6.7	-30.9	30.7	117	227	Hori.	40.0	9.3	
72.023	49.4	QP	6.7	-30.9	25.2	84	100	Vert.	40.0	14.8	
96.134	45.0	QP	9.2	-30.6	23.6	79	304	Hori.	43.5	19.9	
96.134	55.5	QP	9.2	-30.6	34.1	302	100	Vert.	43.5	9.4	
527.989	39.6	QP	18.5	-26.2	31.9	354	183	Hori.	46.0	14.1	
527.998	38.1	QP	18.5	-26.2	30.4	7	113	Vert.	46.0	15.6	
607.135	41.2	QP	19.5	-25.5	35.2	159	126	Hori.	46.0	10.8	
607.134	44.7	QP	19.5	-25.5	38.7	353	100	Vert.	46.0	7.3	
639.088	41.5	QP	19.9	-25.3	36.1	154	123	Hori.	46.0	9.9	
639.089	42.2	QP	19.9	-25.3	36.8	9	100	Vert.	46.0	9.2	
749.993	42.0	QP	21.3	-24.7	38.6	103	100	Hori.	46.0	7.4	
749.991	36.1	QP	21.3	-24.7	32.7	354	100	Vert.	46.0	13.3	
798.140	40.6	QP	22.0	-24.4	38.2	136	111	Hori.	46.0	7.8	
798.220	40.0	QP	22.0	-24.4	37.6	60	123	Vert.	46.0	8.4	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Above 1GHz)

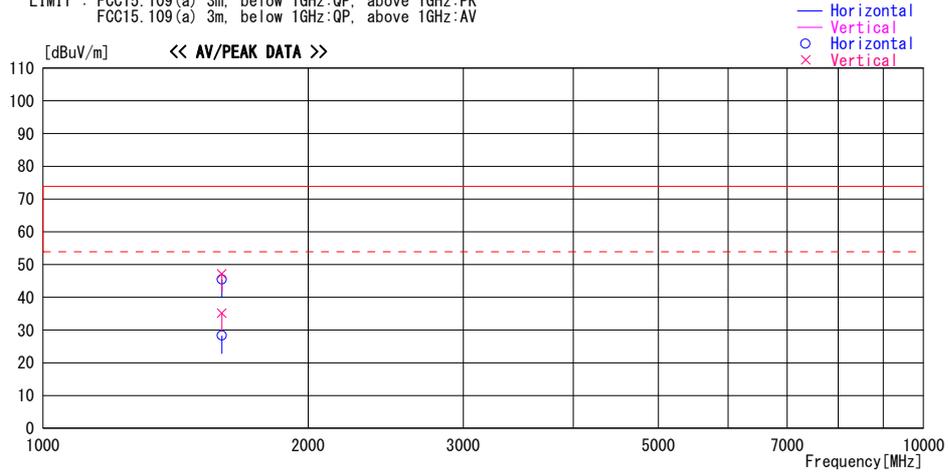
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2012/07/09

Report No. : 32KE0169-H0
Temp./Humi. : 22deg. C / 55% RH
Engineer : Hiroshi Kukita

Mode / Remarks : USB Data Com Mode, Worst axis: X axis

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit	Margin	Comment
			Factor [dB/m]	Gain [dB]					[dBuV/m]	[dB]	
1595.917	54.5	PK	25.8	-34.8	45.5	55	100	Hori.	73.9	28.4	
1595.917	37.4	AV	25.8	-34.8	28.4	55	100	Hori.	53.9	25.5	
1595.927	44.2	AV	25.8	-34.8	35.2	197	100	Vert.	53.9	18.7	
1595.927	56.2	PK	25.8	-34.8	47.2	197	100	Vert.	73.9	26.7	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

*The limit is rounded down to one decimal place.
*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Above 1GHz)

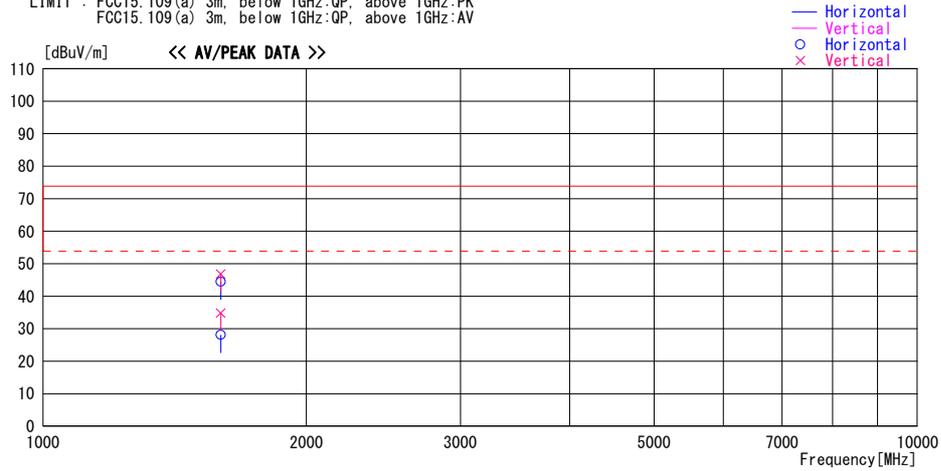
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2012/07/09

Report No. : 32KE0169-H0
Temp./Humi. : 22deg. C / 55% RH
Engineer : Hiroshi Kukita

Mode / Remarks : Standby Mode, Worst axis: X axis

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level	Angle	Height	Polar.	Limit	Margin	Comment
			Factor [dB/m]	Gain [dB]					[dBuV/m]	[dB]	
1595.917	53.5	PK	25.8	-34.8	44.5	72	100	Hori.	73.9	29.4	
1595.917	37.1	AV	25.8	-34.8	28.1	72	100	Hori.	53.9	25.8	
1595.927	43.9	AV	25.8	-34.8	34.9	177	100	Vert.	53.9	19.0	
1595.927	55.9	PK	25.8	-34.8	46.9	177	100	Vert.	73.9	27.0	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The limit is rounded down to one decimal place.
*The test result is rounded off to one or two decimal places, so some differences might be observed.

APPENDIX 2: Test instruments

EMI Test Instruments

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE/CE	2011/07/10 * 12
MOS-27	Thermo-Hygrometer	CUSTOM	CTH-201	A08Q26	RE/CE	2012/02/08 * 12
MJM-01	Measure	KDS	ES19-55	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MTR-09	EMI Test Reseiver	Rohde & Schwarz	ESU26	100412	RE/CE	2012/06/14 * 12
KBA-05	Biconical Antenna	Schwarzbeck	BBA9106	2513	RE	2011/11/23 * 12
KLA-04	Logperiodic Antenna	Schwarzbeck	USLP9143	361	RE	2011/11/23 * 12
MAT-08	Attenuator(6dB)	Weinschel Corp	2	BK7971	RE	2011/11/02 * 12
MCC-02	Coaxial Cable	Suhner/storm/Agilent/TSJ	-	-	RE	2011/09/17 * 12
MPA-19	Pre Amplifier	MITEQ	MLA-10K01-B01-35	1237616	RE	2012/02/20 * 12
MLS-07	LISN(AMN)	Schwarzbeck	NSLK8127	8127364	CE(EUT)	2012/02/09 * 12
MLS-03	LISN(AMN)	Schwarzbeck	NSLK8127	8127384	CE(AE)	2012/03/01 * 12
MTA-29	Terminator	TME	CT-01	-	CE	2012/01/11 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/TSJ	5D-2W(20m)/ 3D-2W(7.5m)/ RG400u(1.5m)/ RFM-E421(Switcher)	-/01068(Switcher)	CE	2012/01/22 * 12
MAT-64	Attenuator(13dB)	JFW Industries, Inc.	50FP-013H2 N	-	CE	2012/01/28 * 12
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2012/06/27 * 12
MCC-134	Microwave Cable	HUBER+SUHNER	SUCOFLEX104	336167/4(1m) / 340641(5m)	RE	2011/09/07 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2012/02/28 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with valid calibrations. Each measurement data is traceable to the national or international standards.

As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

CE: Conducted emission

RE: Radiated emission

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